

Toshiba Intelligent Power Device Silicon Monolithic Power MOS Integrated Circuit

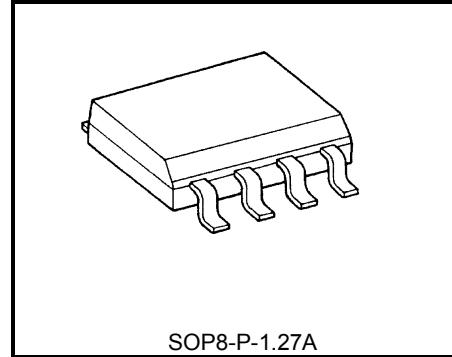
TPD1038F

Motor, Solenoid, Lamp Drivers High-side Power Switch

The TPD1038F is a monolithic power IC for high-side switches. The IC has a vertical MOS FET output which can be directly driven from a CMOS or TTL logic circuit (e.g., an MPU). The device offers intelligent self-protection and diagnostic functions.

Features

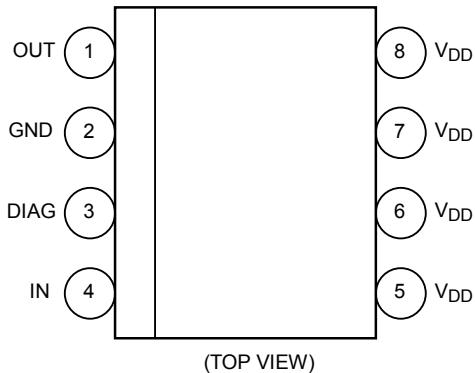
- A monolithic power IC with a structure combining a control block (Bi-CMOS) and a vertical power MOS FET on a single chip.
- One side of load can be grounded to a high-side switch.
- Can directly drive a power load from a microprocessor.
- Built-in protection against overheating and load short-circuiting.
- Incorporates a diagnosis function that allows diagnosis output to be read externally at load short-circuiting, opening, or overheating.
- Up to $-(50-V_{DD}) \sim -(60-V_{DD})$ of counterelectromotive force from an L load can be applied.
- Low on-resistance : $R_{DS(ON)}=120\text{m}\Omega(\text{max})$ (@ $V_{DD} = 12\text{ V}$, $T_a = 25^\circ\text{C}$, $I_o = 2\text{ A}$)
- 8-pin SOP package for surface mounting that can be packed in tape



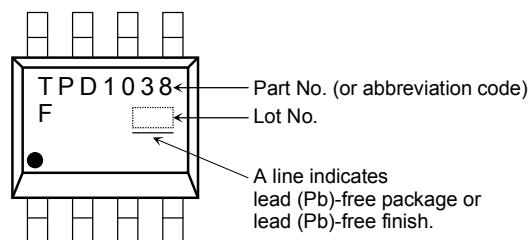
SOP8-P-1.27A

Weight : 0.08g(typ.)

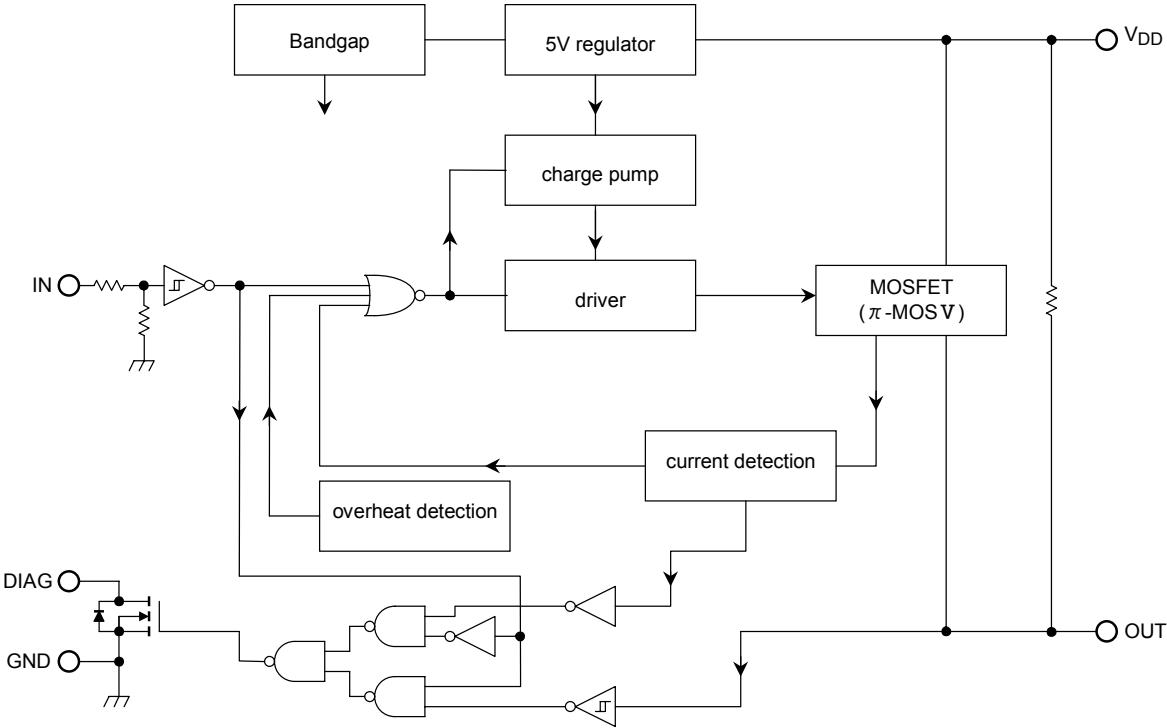
Pin Assignment



Marking

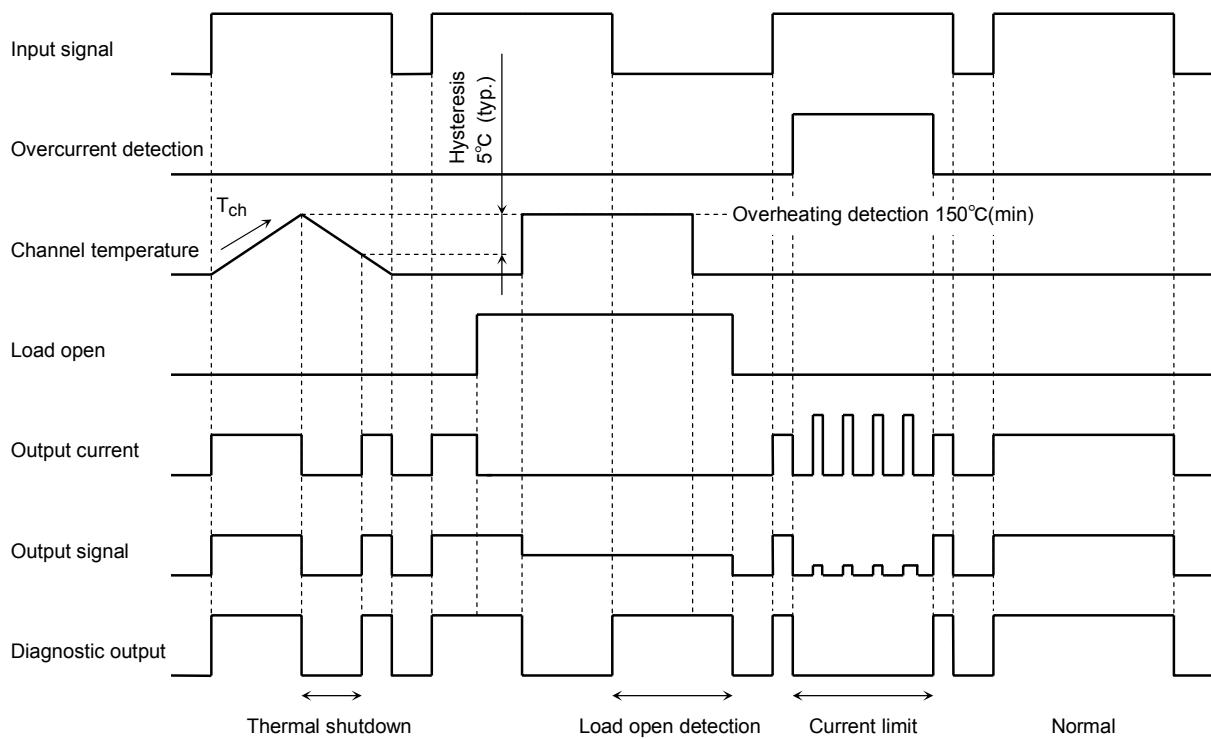


Due to its MOS structure, this product is sensitive to static electricity.

Block Diagram**Pin Description**

Pin No.	Symbol	Function
1	OUT	Output pin. When the load is short-circuited and current in excess of the detection current (3A min) flows to the output pin, the output automatically turns on or off.
2	GND	Ground pin.
3	DIAG	Self-diagnosis detection pin. Goes low when overheating is detected or when output is short circuit with input on (high). N-channel open drain.
4	IN	Input pin. Input is CMOS compatible, with pull down resistor connected. Even if the input is open, output will not accidentally turn on.
5,6,7,8	VDD	Power pin.

Timing Chart



Truth Table

Input signal	Diagnosis output	Output signal	Output state	Operating state
H	H	H	on	Normal
L	L	L	off	
H	L	L	current limit (switching)	Load short
L	L	L	off	
H	L	L	off	Overheating
L	H	H	off	
H	H	H	on	Load open
L	H	H	off	
H	L	L	off	Overheating and load open
L	H	H	off	

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V _{DS}	60	V
Supply voltage	DC	V _{DD(1)}	25	V
	Pulse	V _{DD(2)}	60(R _S =1Ω, τ=250ms)	V
Input voltage	DC	V _{IN(1)}	-0.5~12	V
	Pulse	V _{IN(2)}	V _{DD(1)} +1.5(t=100ms)	V
Diagnosis output voltage		V _{DIAG}	-0.5~25	V
Output current		I _O	Internally limited	A
Input current		I _{IN}	±10	mA
Diagnosis current		I _{DIAG}	5	mA
Power dissipation (Note 1-a)		P _{D(1)}	1.1	W
Power dissipation (Note 1-b)		P _{D(2)}	0.425	W
Operating temperature		T _{opr}	-40~110	°C
Channel temperature		T _{ch}	150	°C
Storage temperature		T _{stg}	-55~150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

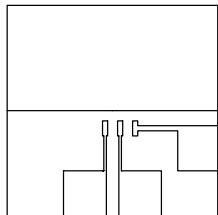
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Thermal Resistance

Characteristic	Symbol	Rating	Unit
Thermal resistance	R _{th(ch-a)}	113.5 (Note1-a)	°C /W
		294.0 (Note1-b)	°C /W

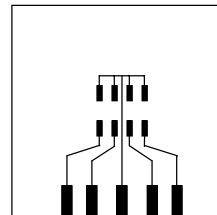
Note 1:

1-a : Mounted on glass epoxy board (a)



FR-4
25.4 × 25.4 × 0.8
(Unit : mm)

1-b : Mounted on glass epoxy board (b)



FR-4
25.4 × 25.4 × 0.8
(Unit : mm)

Electrical Characteristics ($T_a=25^\circ\text{C}$)

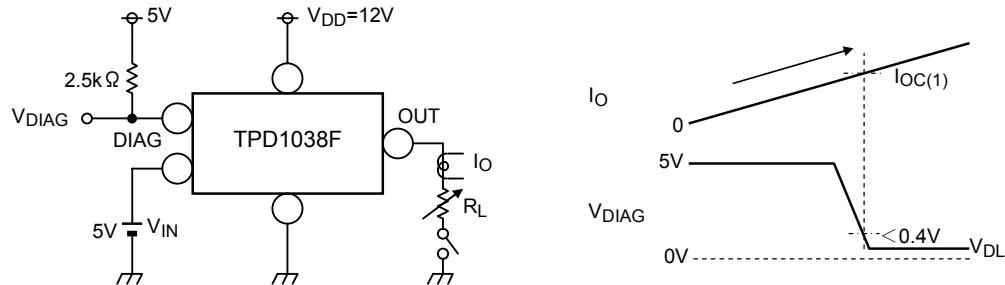
Characteristics	Symbol	Test circuit	Test condition	min	typ.	max	Unit	
Operating supply voltage	$V_{DD(\text{OPR})}$	—	—	6	12	18	V	
Current dissipation	I_{DD}	—	$V_{DD}=12\text{V}, V_{IN}=0\text{V}, R_L=10\Omega$	—	—	3	mA	
H-level input voltage	V_{IH}	—	$V_{DD}=12\text{V}$	3.5	—	—	V	
L-level input voltage	V_{IL}	—	$V_{DD}=12\text{V}$	—	—	1.5	V	
H-level input current	I_{IH}	—	$V_{DD}=12\text{V}, V_{IN}=5\text{V}$	—	—	200	μA	
On resistance	$R_{DS(\text{ON})}$	—	$V_{DD}=12\text{V}, I_O=2\text{A}$	—	—	0.12	Ω	
Output leakage current	I_{OL}	—	$V_{DD}=12\text{V}$	—	—	1	mA	
Diagnosis output voltage	"L"-level	V_{DL}	—	$V_{DD}=12\text{V}, V_{IN}=0\text{V}, I_{DL}=1\text{mA}$ $R_L=10\Omega$	—	—	0.4	V
Diagnosis output current	"H"-level	I_{DH}	—	$V_{DD}=12\text{V}, V_{IN}=5\text{V}, R_L=10\Omega, V_{DH}=12\text{V}$	—	—	10	μA
Over current detection	$I_{OC(1)}$ (Note2)	1.2	$V_{DD}=12\text{V}$	3	—	9	A	
	$I_{OC(2)}$ (Note3)	3	$V_{DD}=12\text{V}, R_L=0.1\Omega$	—	—	10	A	
Overheating detection	T_{OT}	—	$V_{DD}=12\text{V}$	150	—	200	$^\circ\text{C}$	
Load open detection (Note4)	R_{op}	—	$V_{DD}=12\text{V}, V_{IN}=0\text{V}$	5	17	—	$\text{k}\Omega$	
Switching time	t_{on}	4	$V_{DD}=12\text{V}, R_L=10\Omega$	—	—	100	μs	
	t_{off}			—	—	40	μs	
Diagnosis delay time	t_{DLH}	5	$V_{DD}=12\text{V}, R_L=10\Omega$	—	70	—	μs	
	t_{DHL}			—	22	—	μs	
Output clamp voltage	V_{clamp}	—	$V_{DD}=12\text{V}, V_{IN}=0\text{V}, I_O=1\text{A}, L=10\text{mH}$	—(60- V_{DD})	—	—(50- V_{DD})	V	

(Note 2) Over-current detection

(Note 3) Peak current @ current limit function

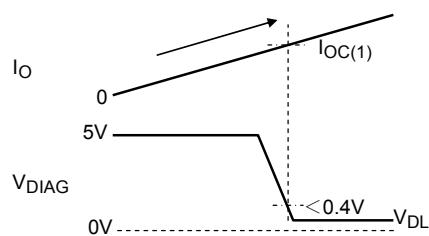
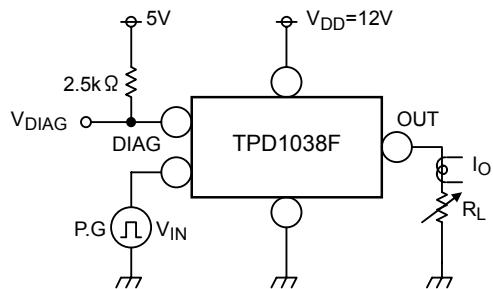
(Note 4) Load open detection function : $V_{DD} = 8 \sim 18\text{V}$

Test Circuit 1

Over current detection $I_{OC(1)}$: Over current detection when load current is increased while V_{IN} = "H"

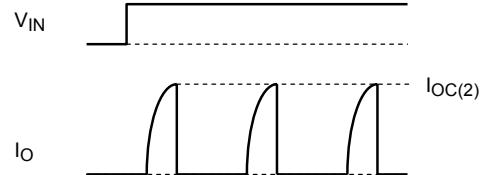
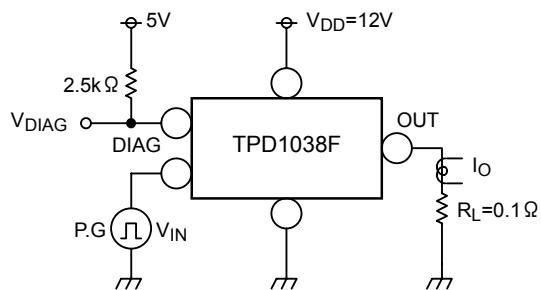
Test Circuit 2

Over current detection $I_{OC(1)}$: Over current detection when load is short circuit and V_{IN} = "L" \rightarrow "H"



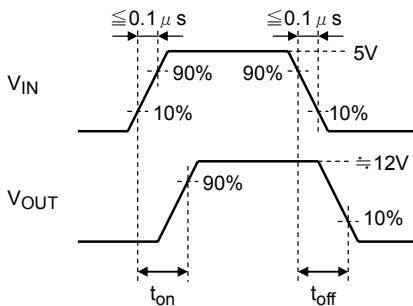
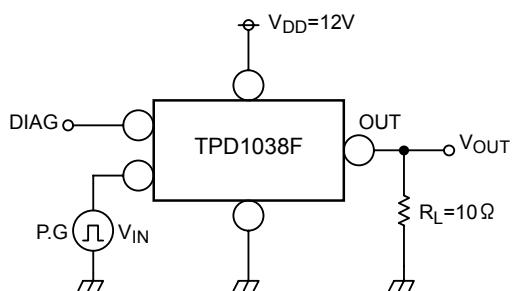
Test Circuit 3

Over current detection $I_{OC(2)}$



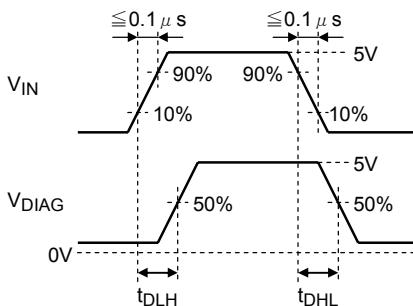
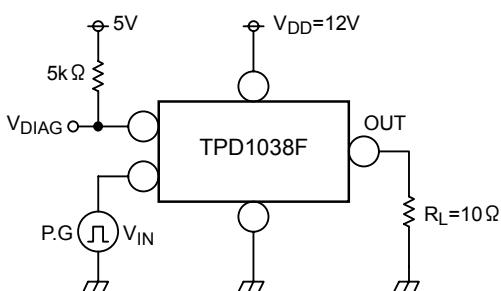
Test Circuit 4

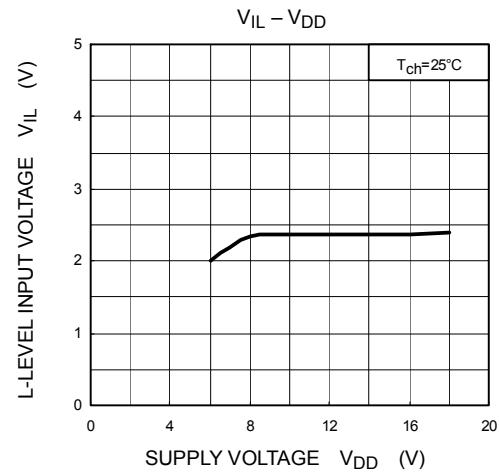
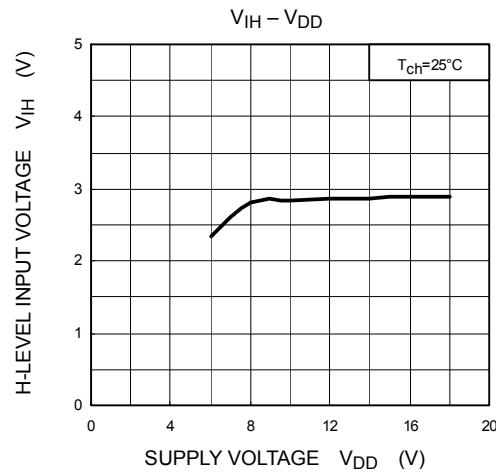
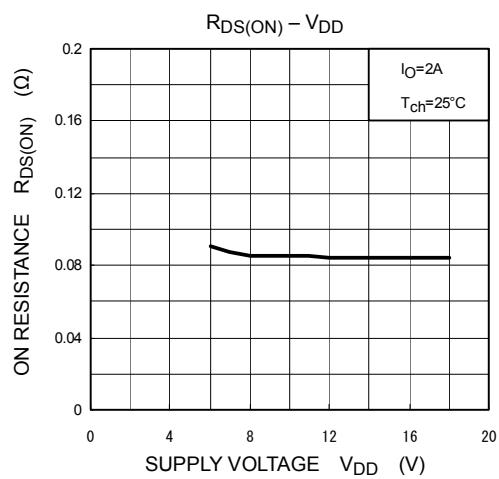
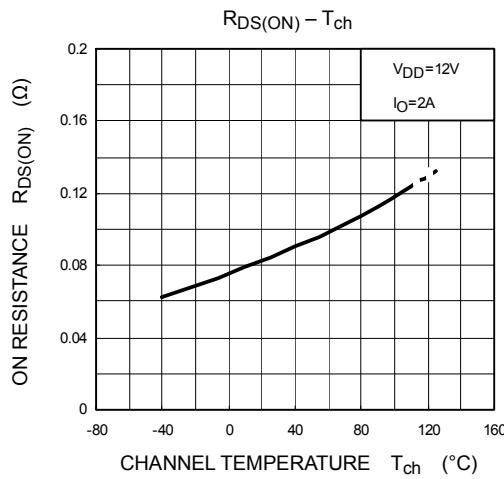
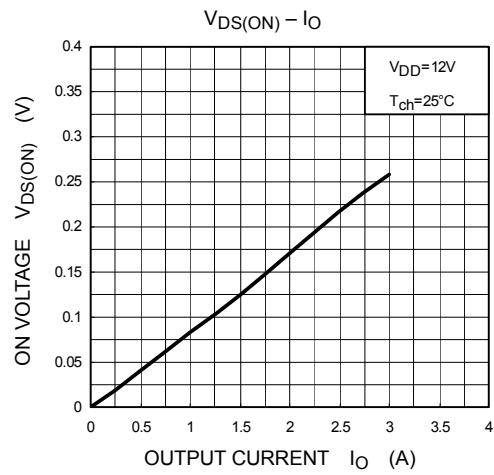
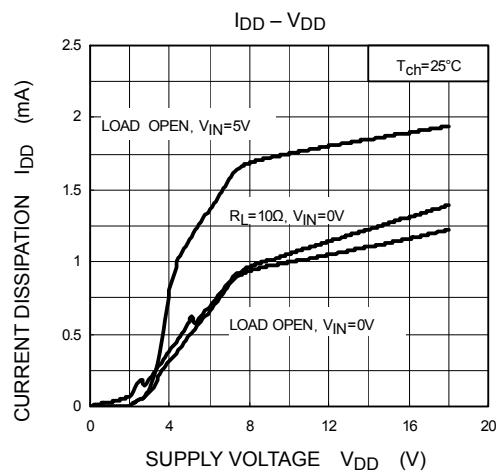
Switching time t_{on}, t_{off}

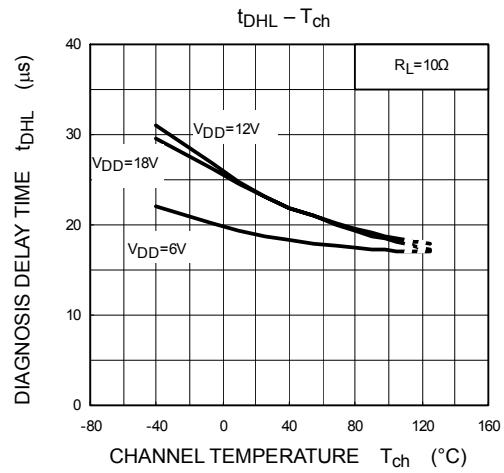
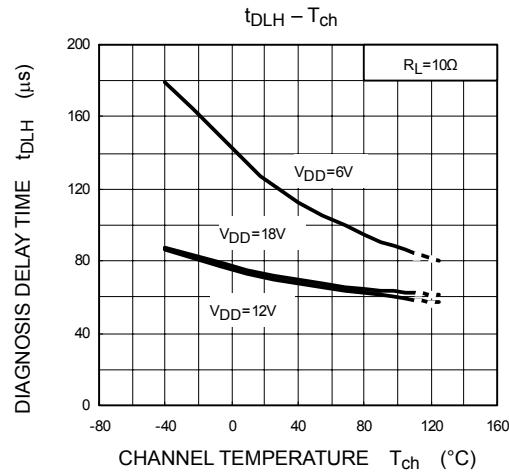
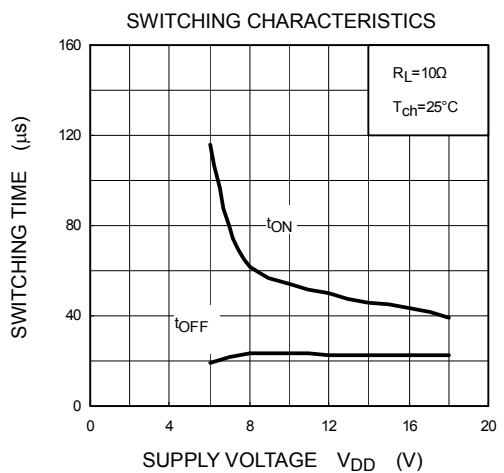
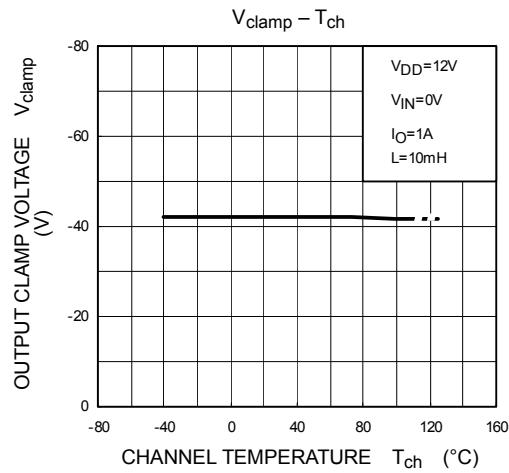
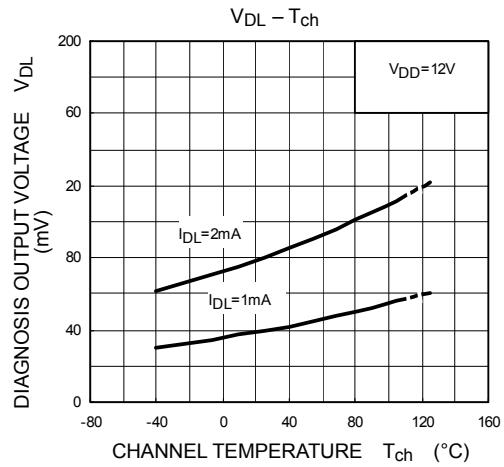
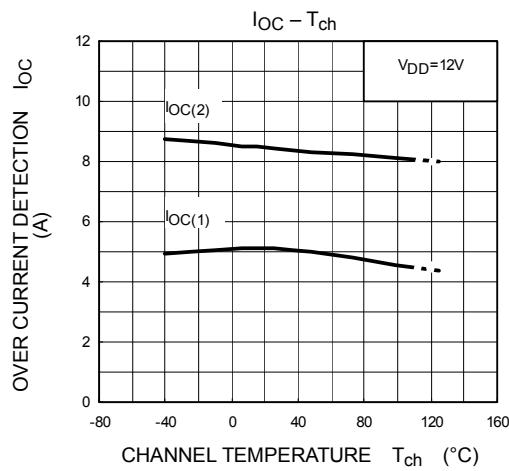


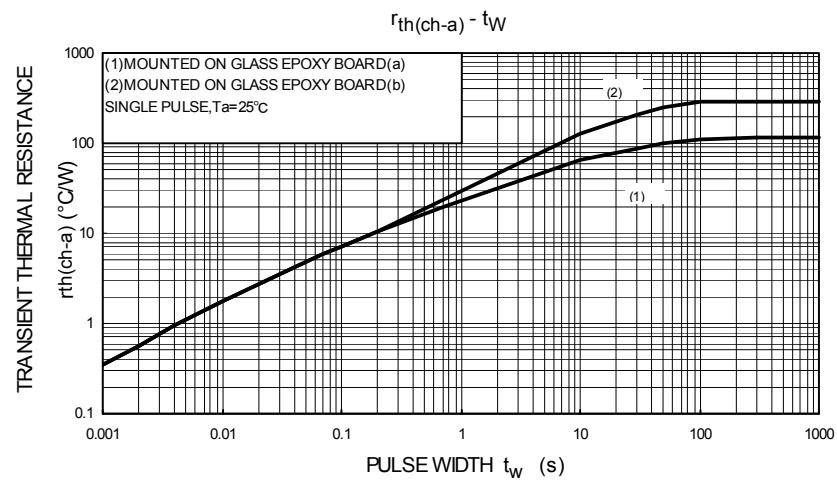
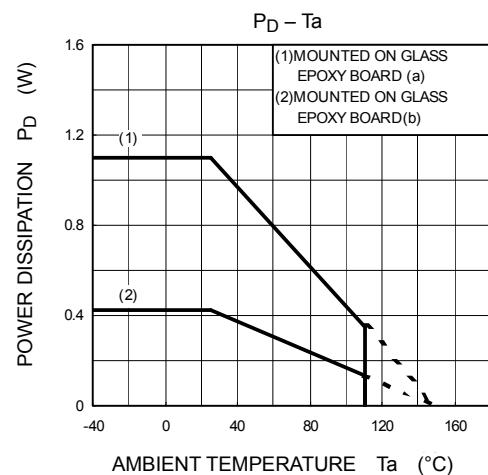
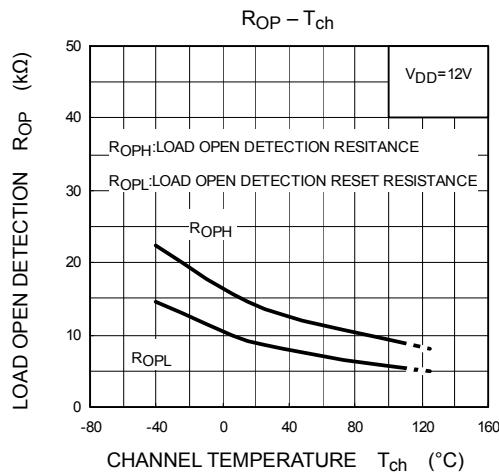
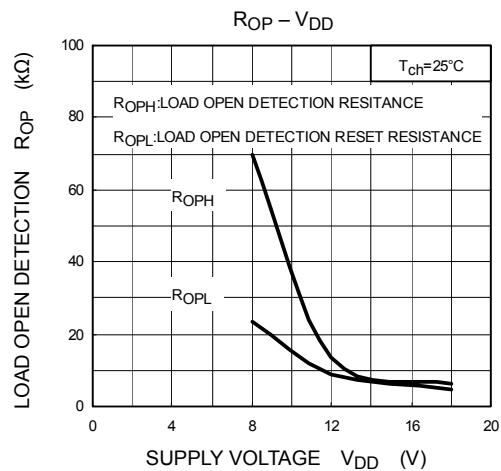
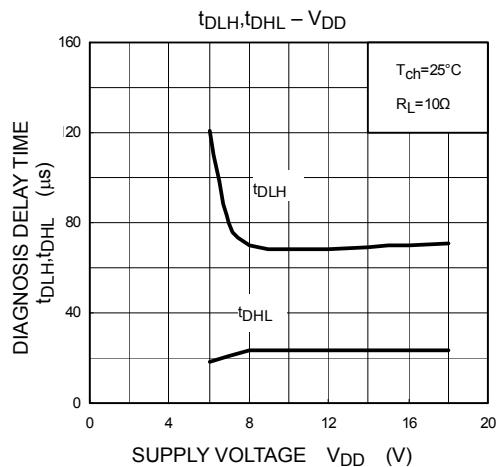
Test Circuit 5

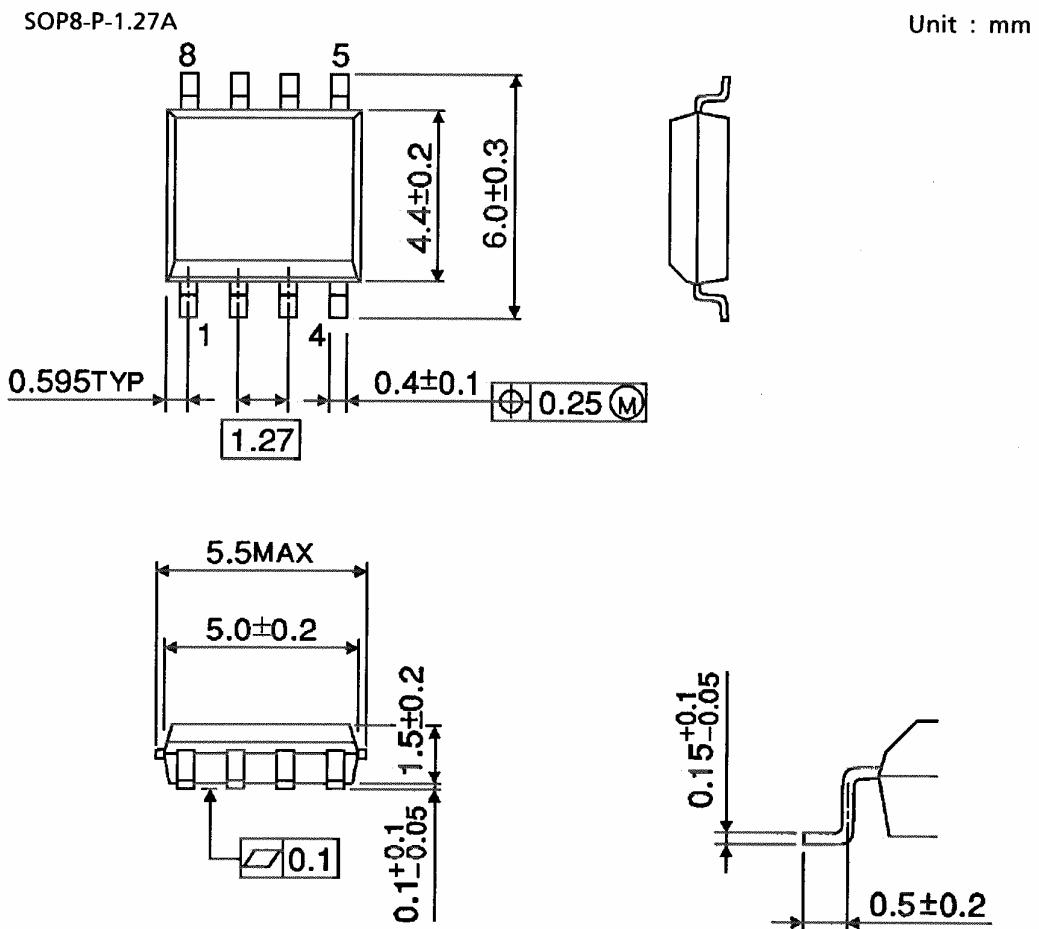
Diagnosis delay time t_{DLH}, t_{DHL}









Package Dimensions

Weight: 0.08g (typ.)

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030619EBA

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